

FEATURES

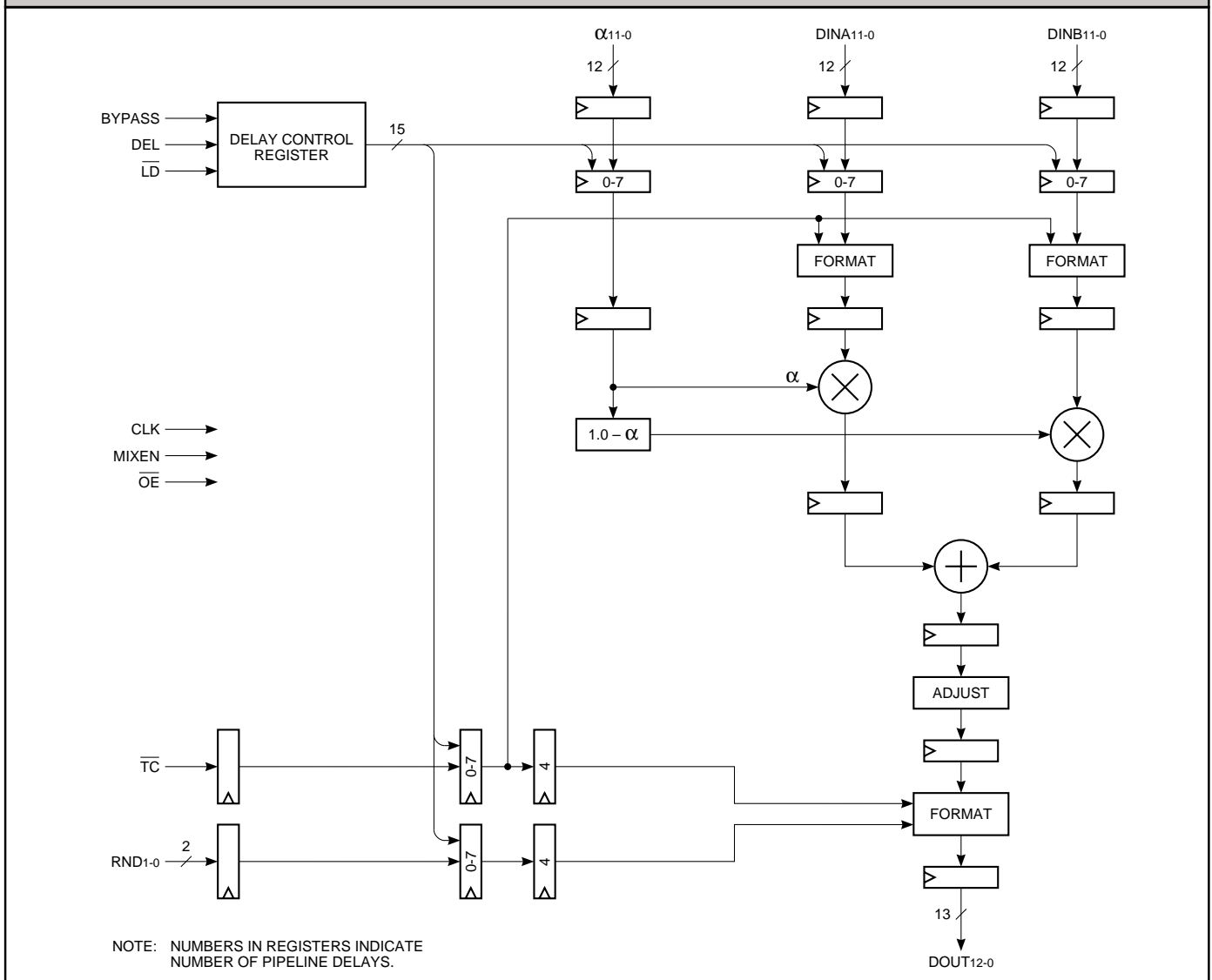
- ❑ 50 MHz Data and Computation Rate
- ❑ Two's Complement or Unsigned Operands
- ❑ On-board Programmable Delay Stages
- ❑ Programmable Output Rounding
- ❑ Replaces Harris HSP48212
- ❑ Package Styles Available:
 - 68-pin PLCC, J-Lead
 - 64-pin PQFP

DESCRIPTION

The LF48212 is a high-speed video alpha mixer capable of mixing video signals at real-time video rates. It takes two 12-bit video signals and mixes them together using an alpha mix factor. Alpha determines the weighting that each video signal receives during the mix operation. The input video data can be in either unsigned or two's complement format, but both inputs must be in the

same format. Independently controlled programmable delay stages are provided for the input and control signals to allow for alignment of input data if necessary. The delay stages can be programmed to have from 0 to 7 delays. The 13-bit output of the alpha mixer is registered with three-state drivers and may be rounded to 8, 10, 12, or 13-bits.

LF48212 BLOCK DIAGRAM



SIGNAL DEFINITIONS

Power

VCC and GND

+5 V power supply. All pins must be connected.

Clock

CLK — Master Clock

The rising edge of CLK strobes all enabled registers except for the Delay Control Register.

Inputs

DINA11-0 — Pixel Data Input A

DINA11-0 is one of the 12-bit registered data input ports. Data is latched on the rising edge of CLK.

DINB11-0 — Pixel Data Input B

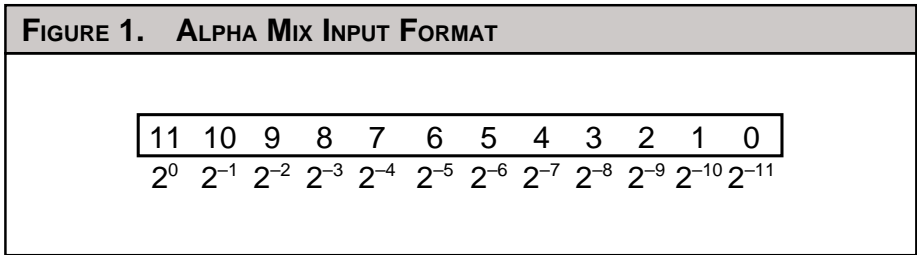
DINB11-0 is the other 12-bit registered data input port. Data is latched on the rising edge of CLK.

α11-0 — Alpha Mix Input

α11-0 determines the weighting applied to the data input signals before being mixed together. DINA11-0 and DINB11-0 receive weightings of α and 1.0 - α respectively. α11-0 is unsigned and restricted to the range of 0 to 1.0. Figure 1 shows the data format for α11-0. If a value greater than 1.0 is latched into the Alpha Mix Input, internal circuitry will force the value to be equal to 1.0. Data is latched on the rising edge of CLK.

DEL — Delay Data Input

DEL is used to load the Delay Control Register. The Delay Control Register contains a 15-bit value which determines the number of delay stages added to the input and control signals. The 15-bit data value is loaded serially into the Delay Control Register using DEL and LD. Data present on DEL is latched on the rising edge of LD.



Outputs

DOUT12-0 — Data Output

DOUT12-0 is the 13-bit registered data output port.

Controls

TC — Data Format Control

TC determines if the input data is in unsigned or two's complement format. If TC is LOW, the data is in two's complement format. If TC is HIGH, the data is in unsigned format. Data present on TC is latched on the rising edge of CLK. TC only affects the data that is being latched into the LF48212. Changing TC does not affect internal data already in the pipeline.

MIXEN — Alpha Mix Input Enable

When HIGH, data on α11-0 is latched into the LF48212 on the rising edge of CLK. When LOW, data on α11-0 is not latched and the last value loaded is held as the alpha mix value.

LD — Load Strobe

The rising edge of LD latches the data on DEL into the Delay Control Register.

BYPASS — Bypass Delay Stage Control

The BYPASS control is used to bypass the internal programmable delay stages. When BYPASS is set HIGH, the Delay Control Register will automatically be loaded with a "0". This will set the number of programmable delay stages to zero for all input and control signals. When BYPASS is LOW, the desired number of delay stages can be set by loading

the Delay Control Register with the appropriate value. Note that this signal is not intended to change during active operation of the LF48212.

RND1-0 — Output Rounding Control

RND1-0 determines how the output of the LF48212 is rounded. The output may be rounded to 8, 10, 12, or 13-bits. Table 1 lists the different rounding possibilities and the associated value for RND1-0. Rounding is accomplished by adding a "1" to the bit to the right of what will become the least significant bit. Then the bit that had the "1" added to it and all bits to the right of it are set to "0". Data present on RND1-0 is latched on the rising edge of CLK. When RND1-0 is latched in, it only applies to the video input data latched in at the same time. Changing RND1-0 does not affect the rounding format for internal data already in the pipeline.

OE — Output Enable

When OE is LOW, DOUT12-0 is enabled for output. When OE is HIGH, DOUT12-0 is placed in a high-impedance state.

TABLE 1. OUTPUT ROUNDING	
RND1-0	ROUNDING FORMAT
00	Round to 8-bits
01	Round to 10-bits
10	Round to 12-bits
11	Round to 13-bits

FUNCTIONAL DESCRIPTION

The two video signals to be mixed together are input to the LF48212 using DINA11-0 and DINB11-0. Data present on DINA11-0 and DINB11-0 is latched on the rising edge of CLK. The input data may be in either unsigned or two's complement format, but both inputs must be in the same format. TC determines the format of the input data. When TC is HIGH, the input data is in unsigned format. When TC is LOW, the input data is in two's complement format. TC is latched on the rising edge of CLK and only affects the input data latched in at the same time. The data already in the pipeline is not affected when TC changes.

DINA11-0 and DINB11-0 are mixed together using an alpha mix factor (α_{11-0}) as defined by the equation listed in Figure 2. α_{11-0} is unsigned and restricted to the range of 0 to 1.0. MIXEN controls the loading of alpha mix data. When MIXEN is HIGH, data present on α_{11-0} is latched on the rising edge of CLK. When MIXEN is LOW, data present on α_{11-0} is not latched and the last value loaded is held as the alpha mix value.

It is possible to add extra delay stages to the input data and control signals by using the programmable delay stages. The 15-bit value (DELAY14-0) stored in the Delay Control Register determines the number of delay stages added. DELAY14-0 is divided into 5 groups of 3-bits each. Each 3-bit group contains the delay information for one of the input data or control signals. Figure 3 shows the block diagram of the Delay Control Register as well as a list of the input data and control signals that may be delayed and the DELAY signals that control them. The delay length can be programmed to be from 0 to 7 stages. The delay length is set by loading the binary equivalent of the desired delay length into the appropriate 3-bit group. For example, to add four extra

delay stages to DINB11-0, DELAY5-3 should be set to "100". DELAY14-0 is loaded serially into the Delay Control Register using DEL and LD. DELAY0 is the first value loaded and DELAY14 is the last. Data present on DEL is latched on the rising edge of LD. BYPASS is used to disable the programmable delay stages. When BYPASS is HIGH, the Delay Control Register is automatically loaded with a "0". This sets all programmable delay stages to a length of zero. When BYPASS is LOW, the Delay Control Register may be loaded to set the desired number of delay stages. Note that BYPASS is not intended to change during active operation of the LF48212.

The Adjust stage of the LF48212 is used to maximize the precision of the output data. Since α can never be larger than 1.0, the most significant bit

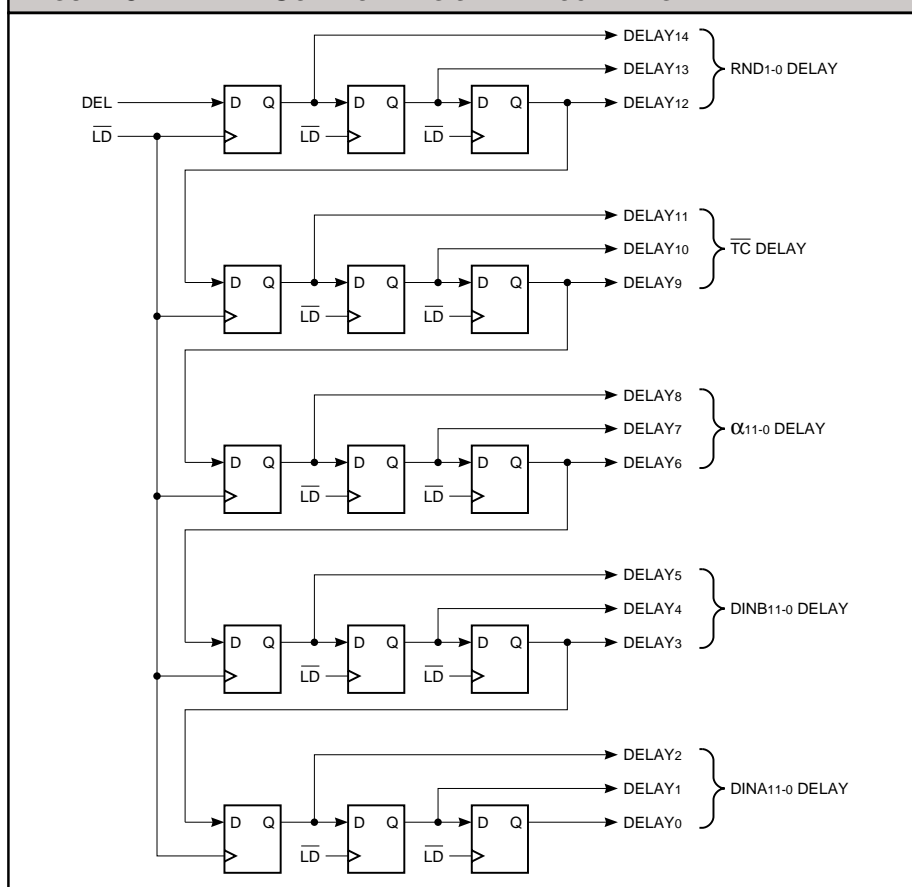
of the internal summer output is not needed. The Adjust stage takes the output of the internal summer and left shifts the data one bit position. This removes the MSB of the internal summer output and provides one more bit of precision for the output data.

The output data of the LF48212 may be rounded to 8, 10, 12, or 13-bits. RND1-0 determines how the output is rounded (See Table 1). RND1-0 is latched on the rising edge of CLK and only affects the input data latched in at the same time. The data already in the pipeline is not affected when RND1-0 changes.

FIGURE 2. OUTPUT EQUATION

$$\text{OUTPUT} = \alpha(\text{DINA}) + (1 - \alpha)\text{DINB}$$

FIGURE 3. DELAY CONTROL REGISTER BLOCK DIAGRAM



MAXIMUM RATINGS *Above which useful life may be impaired (Notes 1, 2, 3, 8)*

Storage temperature	-65°C to +150°C
Operating ambient temperature	-55°C to +125°C
V _{CC} supply voltage with respect to ground	-0.5 V to +7.0 V
Input signal with respect to ground	-0.5 V to V _{CC} + 0.5 V
Signal applied to high impedance output	-0.5 V to V _{CC} + 0.5 V
Output current into low outputs	25 mA
Latchup current	> 400 mA

OPERATING CONDITIONS *To meet specified electrical and switching characteristics*

Mode	Temperature Range (Ambient)	Supply Voltage
Active Operation, Commercial	0°C to +70°C	4.75 V ≤ V _{CC} ≤ 5.25 V

ELECTRICAL CHARACTERISTICS *Over Operating Conditions (Note 4)*

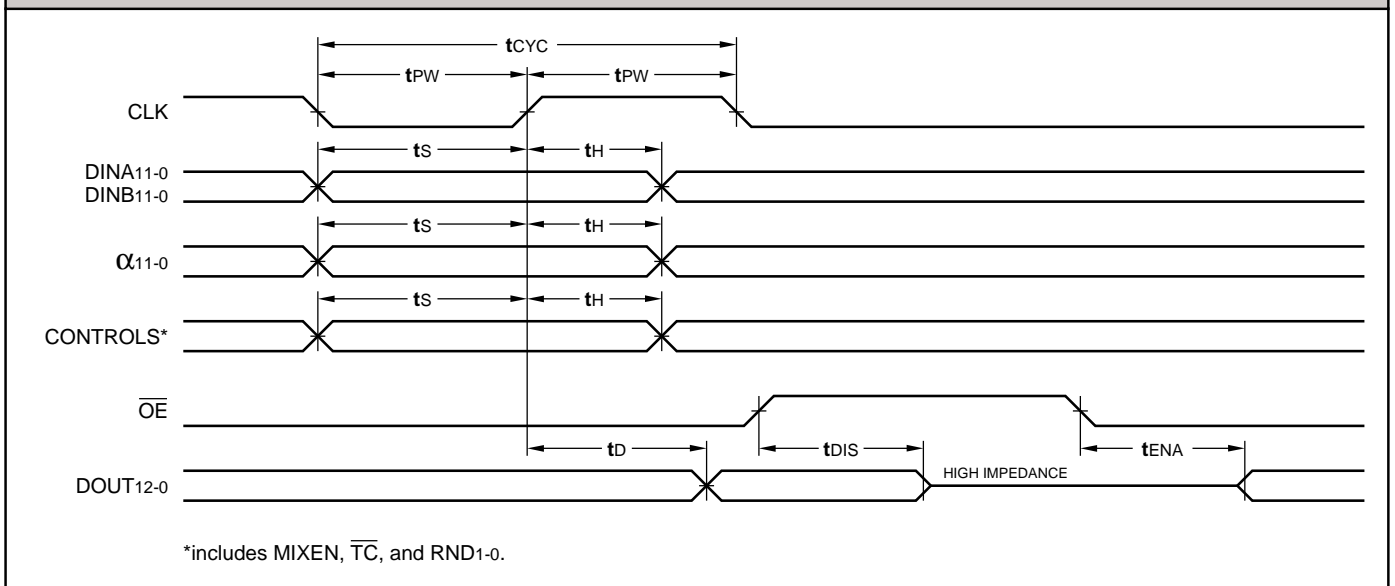
Symbol	Parameter	Test Condition	Min	Typ	Max	Unit
V _{OH}	Output High Voltage	V _{CC} = Min., I _{OH} = -400 μA	2.6			V
V _{OL}	Output Low Voltage	V _{CC} = Min., I _{OL} = 2.0 mA			0.4	V
V _{IH}	Input High Voltage		2.0		V _{CC}	V
V _{IL}	Input Low Voltage	(Note 3)	0.0		0.8	V
I _{IX}	Input Current	Ground ≤ V _{IN} ≤ V _{CC} (Note 12)			±10	μA
I _{OZ}	Output Leakage Current	Ground ≤ V _{OUT} ≤ V _{CC} (Note 12)			±10	μA
I _{CC1}	V _{CC} Current, Dynamic	(Notes 5, 6)			120	mA
I _{CC2}	V _{CC} Current, Quiescent	(Note 7)			500	μA
C _{IN}	Input Capacitance	T _A = 25°C, f = 1 MHz			10	pF
C _{OUT}	Output Capacitance	T _A = 25°C, f = 1 MHz			10	pF

SWITCHING CHARACTERISTICS

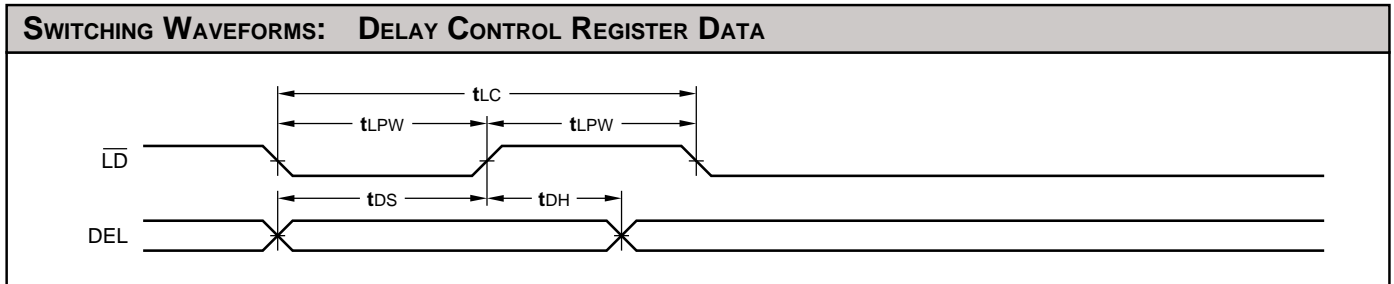
COMMERCIAL OPERATING RANGE (0°C to +70°C) Notes 9, 10 (ns)

Symbol	Parameter	LF48212-			
		25		20	
		Min	Max	Min	Max
t _{CYC}	Cycle Time	25		20	
t _{PW}	Clock Pulse Width	10		10	
t _S	Input Setup Time	11		11	
t _H	Input Hold Time	0		0	
t _D	Output Delay		14		14
t _{ENA}	Three-State Output Enable Delay (Note 11)		13		13
t _{DIS}	Three-State Output Disable Delay (Note 11)		13		13

SWITCHING WAVEFORMS: DATA I/O



COMMERCIAL OPERATING RANGE (0°C to +70°C) Notes 9, 10 (ns)					
Symbol Parameter		LF48212-			
		25		20	
		Min	Max	Min	Max
t_{LC}	LD Cycle Time	25		20	
t_{LPW}	LD Pulse Width	10		10	
t_{DS}	DEL Setup Time	12		12	
t_{DH}	DEL Hold Time	0		0	



NOTES

1. Maximum Ratings indicate stress specifications only. Functional operation of these products at values beyond those indicated in the Operating Conditions table is not implied. Exposure to maximum rating conditions for extended periods may affect reliability.

2. The products described by this specification include internal circuitry designed to protect the chip from damaging substrate injection currents and accumulations of static charge. Nevertheless, conventional precautions should be observed during storage, handling, and use of these circuits in order to avoid exposure to excessive electrical stress values.

3. This device provides hard clamping of transient undershoot and overshoot. Input levels below ground or above VCC will be clamped beginning at -0.6 V and VCC + 0.6 V. The device can withstand indefinite operation with inputs in the range of -0.5 V to +7.0 V. Device operation will not be adversely affected, however, input current levels will be well in excess of 100 mA.

4. Actual test conditions may vary from those designated but operation is guaranteed as specified.

5. Supply current for a given application can be accurately approximated by:

$$\frac{NCV^2F}{4}$$

where

- N = total number of device outputs
- C = capacitive load per output
- V = supply voltage
- F = clock frequency

6. Tested with all outputs changing every cycle and no load, at a 40 MHz clock rate.

7. Tested with all inputs within 0.1 V of VCC or Ground, no load.

8. These parameters are guaranteed but not 100% tested.

9. AC specifications are tested with input transition times less than 3 ns, output reference levels of 1.5 V (except tDIS test), and input levels of nominally 0 to 3.0 V. Output loading may be a resistive divider which provides for specified IOH and IOL at an output voltage of VOH min and VOL max respectively. Alternatively, a diode bridge with upper and lower current sources of IOH and IOL respectively, and a balancing voltage of 1.5 V may be used. Parasitic capacitance is 30 pF minimum, and may be distributed.

This device has high-speed outputs capable of large instantaneous current pulses and fast turn-on/turn-off times. As a result, care must be exercised in the testing of this device. The following measures are recommended:

a. A 0.1 μF ceramic capacitor should be installed between VCC and Ground leads as close to the Device Under Test (DUT) as possible. Similar capacitors should be installed between device VCC and the tester common, and device ground and tester common.

b. Ground and VCC supply planes must be brought directly to the DUT socket or contactor fingers.

c. Input voltages should be adjusted to compensate for inductive ground and VCC noise to maintain required DUT input levels relative to the DUT ground pin.

10. Each parameter is shown as a minimum or maximum value. Input requirements are specified from the point of view of the external system driving the chip. Setup time, for example, is specified as a minimum since the external system must supply at least that much time to meet the worst-case requirements of all parts. Responses from the internal circuitry are specified from the point of view of the device. Output delay, for example, is specified as a maximum since worst-case operation of any device always provides data within that time.

11. For the tENA test, the transition is measured to the 1.5 V crossing point with datasheet loads. For the tDIS test, the transition is measured to the ±200mV level from the measured steady-state output voltage with ±10mA loads. The balancing voltage, VTH, is set at 3.5 V for Z-to-0 and 0-to-Z tests, and set at 0 V for Z-to-1 and 1-to-Z tests.

12. These parameters are only tested at the high temperature extreme, which is the worst case for leakage current.

FIGURE A. OUTPUT LOADING CIRCUIT

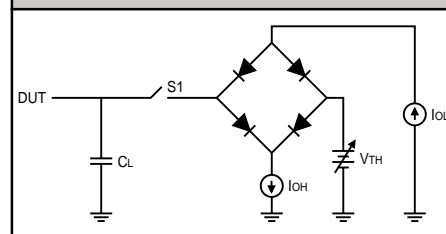
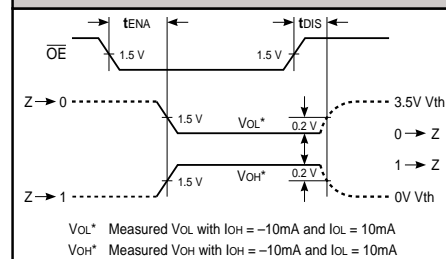
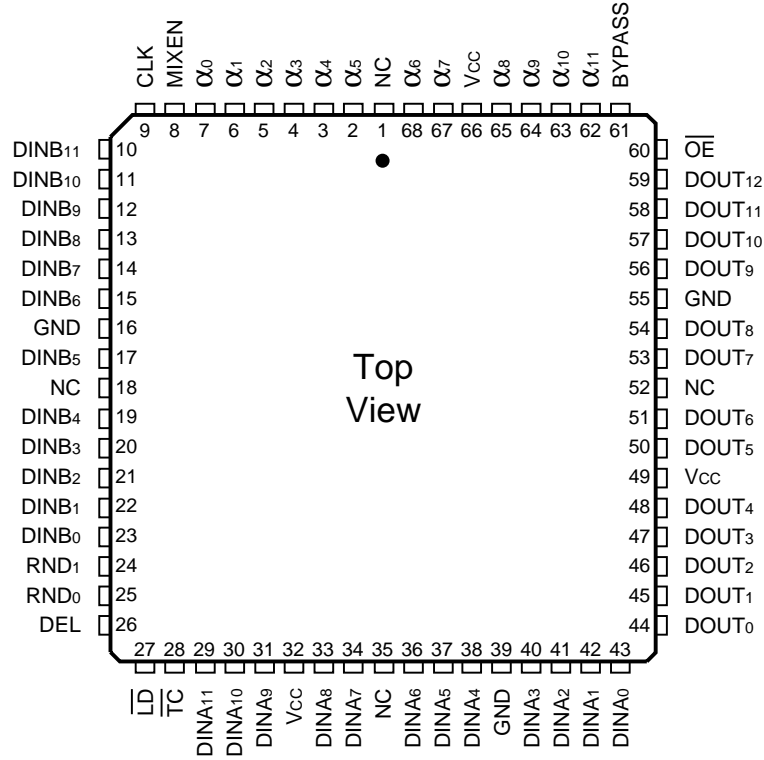


FIGURE B. THRESHOLD LEVELS



ORDERING INFORMATION

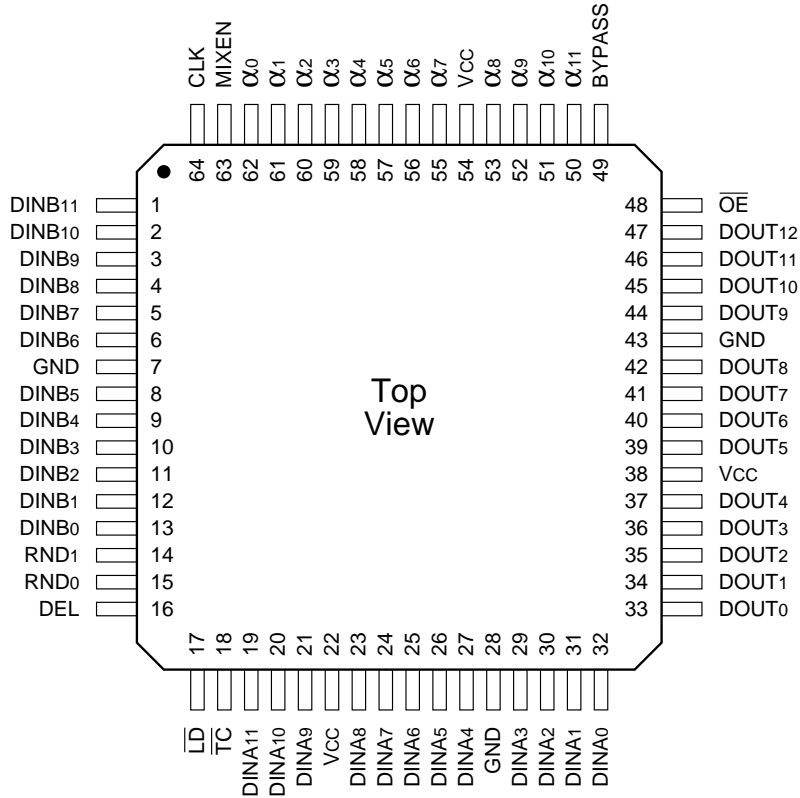
68-pin



Speed	Plastic J-Lead Chip Carrier (J2)
	0°C to +70°C — COMMERCIAL SCREENING
25 ns	LF48212JC25
20 ns	LF48212JC20

ORDERING INFORMATION

64-pin



Speed	Plastic Quad Flatpack (Q3)	
	0°C to +70°C — COMMERCIAL SCREENING	
25 ns	LF48212QC25	
20 ns	LF48212QC20	